

Qualification Description:

The information contained herein represents proof of Reliability and Performance of the Package Series listed below in accordance with the Qualification Plan and test methods referenced in Section 7.0, after exposure to a variety of environments and mechanical events that occur during installation and operational lifetime of the product. Upon conclusion of the testing the product continued to operate within specification limits, demonstrating its capability of reliable operation throughout its lifetime.

The purpose of this report is to present Qualification Test results of the referenced Package Series. The Pericom product data presented in this report qualifies the products manufactured in this package configuration, using the same bill of materials and assembled by the identified subcontractor location. The report describes the qualification test program, procedures utilized, criteria enforced (at the time of product validation), and specific result data obtained during the testing of three lots of semiconductors. The three lots consist of an equal number of units from different date codes, from the same production line and SubContractor to ensure manufacturing repeatability.

Lot Background Information:

Qual Part Number:	PI7C9X440SLBFDE
Supplier (Code):	GTK (G)
Pkg Type - Code:	LQFP-128 e-pad (FDE128)
Outline Drawing:	PD-2072
By Extension Pkg:	FA48 FA32

Qual Test Date:	Oct-2011
Die Attach Material:	1076DJ-G
Wire Size & Material:	0.8 mil Gold
Mold Compound:	G700HA
Leadframe Material:	C7025 Copper
Lead Finish:	100% Matte Sn

Date Codes: 1119GI, 1120GI

Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Preconditioning	JESD22-A113	MSL3	NA	2	154	154 / 0
CSAM	J-STD-020	No delamination of Die Top, Wire bond, Down bond areas	NA	2	22	22 / 0
PreCon UHAST	JESD22-A118	130°C, RH 85%, 33.3 psia, 0V	96 hrs	2	77	77 / 0
PreCon Temp Cycle	JESD22-A104	-65°C to +150°C 500 Cycles	100 cycles	2	77	77 / 0
		-65°C to +150°C 500 Cycles	500 cycles	2	77	77 / 0
PreCon B-HAST	JESD22-A110	130°C, RH 85%, 33.3 psia, 3.3V	96 hrs	2	77	77 / 0
HTSL (no PreCon)	JESD22-A103	1000hrs, 0V, 150°C	500 hrs	2	77	77 / 0
		1000hrs, 0V, 150°C	1000 hrs	2	77	77 / 0
Physical Dimension	JESD22-B100	Per Datasheet	NA	2	5	5 / 0
External Visual Insp	JESD22-B101	NA	NA	2	5	5 / 0
Solderability	J-STD-020 JESD22-B102	Pb-Free Solder Dip 245°C	NA	2	5	5 / 0

Qualification by Extension Information:

Where a product of interest is not sampled during this period, it is valid to use the reliability data of the particular process technology or package type family to which the part belongs. All parts within the same family are designed to the same rules, and manufacturing is controlled by SPC. Within a product family, a device can only be fabricated on one process technology/ option, and only assembled on one package type process.

If there are any questions about this qualification, please contact Quality Support at:

customerquestion@pericom.com

Package Qualification Report

Reliability By Design

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Lot Background Information:

Qual Part Number:	Internal PN
Supplier (Code):	OSE (O)
Pkg Type - Code:	TQFP-64
Outline Drawing:	not available
By Extension Pkg:	FA48 FA32

Qual Test Date:	May-2010
Die Attach Material:	Hitachi EN4900G
Wire Size & Material:	0.8 mil Gold
Mold Compound:	Hitachi CEL9200HF
Leadframe Material:	Copper
Lead Finish:	100% Matte Sn

Date Codes: 0945

Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Preconditioning	JESD22-A113	MSL1	NA	1	135	135 / 0
CSAM	J-STD-020	No delamination of Die Top, Wire bond, Down bond areas	NA	1	20	20 / 0
PreCon UHAST	JESD22-A118	130°C, RH 85%, 33.3 psia, 0V	96 hrs	1	45	45 / 0
PreCon Temp Cycle	JESD22-A104	-65°C to +150°C 500 Cycles	100 cycles	1	45	45 / 0
		-65°C to +150°C 500 Cycles	500 cycles	1	45	45 / 0
Physical Dimension	JESD22-B100	Per Datasheet	NA	1	5	5 / 0
External Visual Insp	JESD22-B101	NA	NA	1	5	5 / 0
Terminal Strength	JESD22-B105	90° Bends, 2 bend min.	NA	1	5	5 / 0
Solderability	J-STD-020	Pb-Free Solder Dip 245°C	NA	1	5	5 / 0
	JESD22-B102					

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